

Sheet 1 of 1

FORM PTD-1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.: FIS920010192U51	SERIAL NO.: 09/977,793
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT: Christopher P. Ausschnitt et al.	
(Use several sheets if necessary) (37 CFR 1.98(b))		FILING DATE: 10/15/01	GROUP: 2877

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
<i>WD</i>	AA	5,545,593	08/13/96	Watkins et al.	—	—	
<i>WD</i>	AB	5,877,861	03/02/99	Ausschnitt et al.	—	—	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

			PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION	
	AM	DOCUMENT NUMBER					YES	NO
	AN							
	AO							
	AP							
	AQ							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	
	ARS	
	AT	

EXAMINER

*William Davis*

DATE CONSIDERED

*5-23-03*

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 3

FORM PTO-1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.: FI5920010192US1	SERIAL NO.: 09/977,793
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT: Christopher P. Ausschnitt et al.	
(Use several sheets if necessary) (37 CFR 1.98(b))		FILING DATE: October 15, 2001	GROUP: 2877

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
WD	AA	4,568,189	2/4/86	Bass et al.			
	AB	4,898,911	7/18/89	Uchida et al.			
	AC	5,343,292	8/30/94	Brueck et al.			
	AD	5,545,593	8/13/96	Watkins et al.			
	AE	5,629,772	5/13/97	Ausschnitt			
	AF	5,712,707	1/27/98	Ausschnitt et al.			
	AG	5,731,877	3/24/98	Ausschnitt			
	AH	5,756,242	5/26/98	Koizumi et al.			
	AI	5,757,507	5/26/98	Ausschnitt et al.			
	AJ	5,776,645	7/7/98	Barr et al.			
	AK	5,790,254	8/4/98	Ausschnitt			
	AL	5,805,290	9/8/98	Ausschnitt et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION YES NO
	AM	<del>JP 10-213895 A</del>	<del>8/11/98</del>	<del>Japan</del>			
	AN	<del>JP 61-168227 A</del> (Abstract only)	<del>7/29/86</del>	<del>Japan</del>			
	AO	<del>JP 61-170032 A</del> (Abstract only)	<del>7/31/86</del>	<del>Japan</del>			
	AP	<del>JP 2-260441 A</del> (Abstract only)	<del>10/23/90</del>	<del>Japan</del>			

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AQ	<del>Starikov, Alexander, "Exposure Monitor Structure", SPIE Vol. 1261, Integrated Circuit Metrology, Inspection and Process Control IV, 1990, pages 315-324.</del>
	AR	<del>"Method for Measuring Semiconductor Lithographic Tool Focus and Exposure", IBM Technical Disclosure Bulletin, July 1987, pages 516-518.</del>
	AS	

EXAMINER

Willie Davis

DATE CONSIDERED

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Sheet 2 of 3

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(Use several sheets if necessary) (37 CFR 1.98(b))		FILING DATE: October 15, 2001	GROUP: 2877

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
WD	AT	5,877,861	3/2/99	Ausschnitt et al.			
	AU	5,914,784	6/22/99	Ausschnitt et al.			
	AV	5,928,822	7/27/99	Rhyu			
	AW	5,949,547	9/7/99	Tseng et al.			
	AX	5,952,134	9/14/99	Hwang			
	AY	5,953,128	9/14/99	Ausschnitt et al.			
	AZ	5,965,309	10/12/99	Ausschnitt et al.			
	BA	5,968,693	10/19/99	Adams			
	BB	5,976,740	11/2/99	Ausschnitt et al.			
	BC	5,981,119	11/9/99	Adams			
	BD	5,985,495	11/16/99	Okumura et al.			
	BE	6,003,223	12/21/99	Hagen et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION YES NO
	BF						
	BG						
	BH						

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

BI	
BJ	
BK	
EXAMINER	DATE CONSIDERED
Willie Davis	5-23-03
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Sheet 3 OF 3

<b>FORM PTO-1449</b> <b>(Modified)</b> <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE</b> <b>STATEMENT BY APPLICANT</b>  (Use several sheets if necessary) (37 CFR 1.98(b))	<b>ATTY. DOCKET NO.:</b> FIS920010192U51	<b>SERIAL NO.:</b> 09/977,793
	<b>APPLICANT:</b> Christopher P. Ausschnitt et al.	
	<b>FILING DATE:</b> October 15, 2001	<b>GROUP:</b> 2877

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
W	BL	6,004,706	12/21/99	Ausschnitt et al.			
	BM	6,020,966	2/1/00	Ausschnitt et al.			
	BN	6,027,842	2/22/00	Ausschnitt et al.			
	BO	6,042,976	3/28/00	Chiang et al.			
	BP	6,128,089	10/3/00	Ausschnitt et al.			
	BQ	6,130,750	10/10/00	Ausschnitt et al.			
	BR	6,137,578	10/24/00	Ausschnitt			
	BS	6,183,919	2/6/01	Ausschnitt et al.			
	BT	6,317,211	11/13/01	Ausschnitt et al.			
	BU	6,346,979	2/12/02	Ausschnitt et al.			
	BV						
	BW						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	BX							
	BY							
	BZ							
	CA							
	CB							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	CC	
	CD	
	CE	

<b>EXAMINER</b> <i>Willie Davis</i>	<b>DATE CONSIDERED</b> 5-23-03
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